

AUG 2 9 2005



INFORMATION DISCLOSURE
STATEMENT BY APPLICANTS
PTO FORM 1449

Atty. Docket No. 10191/4246	Serial No. 10/534,603
Applicant(s) HARTER et al.	
Filing Date May 11, 2005	Group To Be Assigned

U. S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
						YES NO

OTHER DOCUMENTS

EXAMINER'S INITIALS	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
/SR/	M. Abramovici et al., "Digital Systems Testing And Testable Design", IEEE Press 1990. *
/SR/	R. N. Williams "A Painless Guide to CRC Error Detection Algorithms, Version 3, 8/19/1993, Rocksoft^tm Pty Ltd. Australia. *

*Described in the Specification.

EXAMINER	/Samir Rizk/ (02/20/2008)	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		